

2-Propanol

VLSI

(iso-propyl alcohol)



Material No.: 5373-05
Batch No.: 0000001423
Manufactured Date: 2012/04/20

Certificate of Analysis

Test	Specification	Result
Assay (CH ₃ CHOHCH ₃)	>= 99.5 %	100.0
Color (APHA)	<= 10	5
Residue after Evaporation	<= 4 ppm	< 1
Solubility in H ₂ O	Passes Test	PT
Water (H ₂ O)(by Karl Fischer titrn)	<= 0.05 %	0.02
Acidity (µeq/g)	<= 0.2	< 0.0
Alkalinity (µeq/g)	<= 0.1	< 0.0
Chloride (Cl)	<= 0.1 ppm	< 0.1
Phosphate (PO ₄)	<= 0.3 ppm	< 0.3
Trace Impurities –Aluminum (Al)	<= 50 ppb	< 5
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities –Barium (Ba)	<= 20 ppb	< 1
Trace Impurities –Boron (B)	<= 10 ppb	< 5
Trace Impurities –Cadmium (Cd)	<= 20 ppb	< 1
Trace Impurities –Calcium (Ca)	<= 50 ppb	2
Trace Impurities –Chromium (Cr)	<= 20 ppb	< 1
Trace Impurities –Cobalt (Co)	<= 20 ppb	< 1
Trace Impurities –Copper (Cu)	<= 10 ppb	< 1
Trace Impurities –Gallium (Ga)	<= 50 ppb	< 1
Trace Impurities –Germanium (Ge)	<= 50 ppb	< 1
Trace Impurities –Gold (Au)	<= 20 ppb	< 5
Heavy Metals (as Pb)	<= 200 ppb	< 100
Trace Impurities –Iron (Fe)	<= 50 ppb	< 1
Trace Impurities –Lead (Pb)	<= 20 ppb	< 10

Test	Specification	Result
Trace Impurities –Lithium (Li)	≤ 50 ppb	<1
Trace Impurities –Magnesium (Mg)	≤ 20 ppb	<1
Trace Impurities –Manganese (Mn)	≤ 20 ppb	<1
Trace Impurities –Nickel (Ni)	≤ 10 ppb	<5
Trace Impurities –Potassium (K)	≤ 100 ppb	<10
Trace Impurities –Silicon (Si)	≤ 50 ppb	<10
Trace Impurities –Silver (Ag)	≤ 20 ppb	<1
Trace Impurities –Sodium (Na)	≤ 100 ppb	<5
Trace Impurities –Strontium (Sr)	≤ 20 ppb	<1
Trace Impurities –Tin (Sn)	≤ 100 ppb	<10
Trace Impurities –Titanium (Ti)	≤ 20 ppb	<1
Trace Impurities –Zinc (Zn)	≤ 50 ppb	<1
Particle Count –0.5 µm and greater	≤ 100 par/ml	4
Particle Count –1.0 µm and greater	≤ 8 par/ml	1

For Microelectronic Use

Reported value is the average of all samples counted for this lot number,with no individual sample value exceeding the specification.

Storage Conditions:

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC

ISO

Phillipsburg, NJ 9001.2008, 14001.2004
Paris, KY 9001.2008
Mexico city, Mexico 9001.2008
Deventer, The Netherlands 9001.2008, 14001.2004
Selangor, Malaysia 9001.2008
Panoli, India 9001.2008
Gliwice, Poland 9001.2008,17025.2005

Richard M Siberski
Global Director of Quality Assurance